Searcn Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination		
10/781,766	HON ET AL.	HON ET AL.	
Examiner	Art Unit	Art Unit	
Cuong Q. Nguyen	2811	2811	

SEARCHED			
Class	Subclass	Date	Examiner
257	88-103	2-15-06	a

see INTERFERENCE SEARCHED note			
Class	Subclass	Date	Examiner
			-
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST + EPO+JPO	2-15-96	a